



Optical Link of the ATLAS Pixel Detector

K.K. Gan
The Ohio State University

October 20, 2005

W. Fernando, K.K. Gan, P.D. Jackson, M. Johnson, H. Kagan, A. Rahimi, R. Kass, S. Smith

<u>The Ohio State University</u>

P. Buchholz, M. Holder, A. Roggenbuck, P. Schade, M. Ziolkowski Universitaet Siegen, Germany



Outline



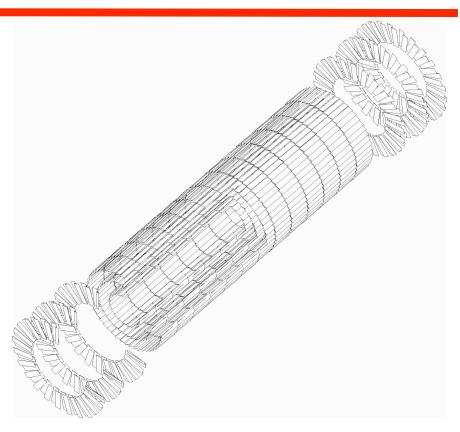
- Introduction
- Proton Irradiation Studies
- Production Status
- Summary



ATLAS Pixel Detector



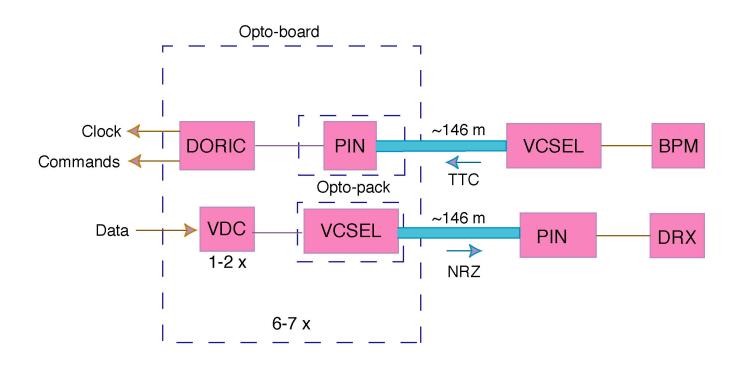
- Inner most tracking detector
- Pixel size: 50 μm x 400 μm
- 100 million channels
- Barrel layers at r = 5.1-12.3 cm
- Disks at z = 50-65 cm
- Dosage after 10 years:
 - optical link: 17 Mrad or 3.7 x 10^{14} 1-MeV n_{eq}/cm^2





ATLAS Pixel Opto-link





VCSEL: Vertical Cavity Surface Emitting Laser diode

VDC: VCSEL Driver Circuit

PIN: PiN diode

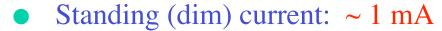
DORIC: Digital Optical Receiver Integrated Circuit



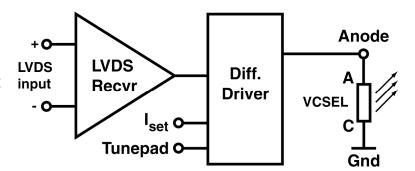
VDC: VCSEL Driver Circuit



- Convert LVDS input signal into single-ended signal appropriate to drive VCSEL diode
- Output (bright) current: 0 to 20 mA
 - controlled by external current I_{set}



improve switching speed



- Rise & fall times: 1 ns nominal for 40 MHz signals
- "On" voltage of VCSEL: up to 2.3 V at 20 mA for 2.5 V supply
- Constant current consumption!
- Use IBM 0.25 μm CMOS
- Use Truelight high-power oxide common cathode VCSEL array
 K.K. Gan

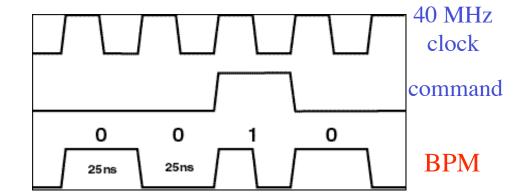


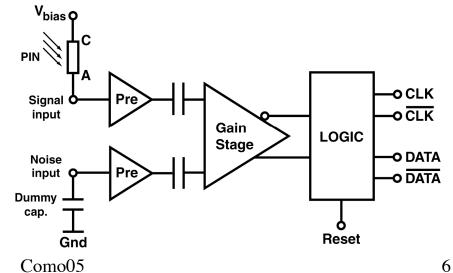
DORIC: Digital Optical Receiver IC

- Decode Bi-Phase Mark encoded (BPM) clock and command
- Input signal: 40-1000 µA

signals from PIN diode

- Extract: 40 MHz clock
- Duty cycle: $(50 \pm 4)\%$
- Total timing error: < 1 ns
- Bit Error Rate (BER): < 10⁻¹¹ at end of life
- Use IBM 0.25 µm CMOS
- Use Truelight common cathode PIN array (Taiwan)





K.K. Gan



Opto-board Design/History

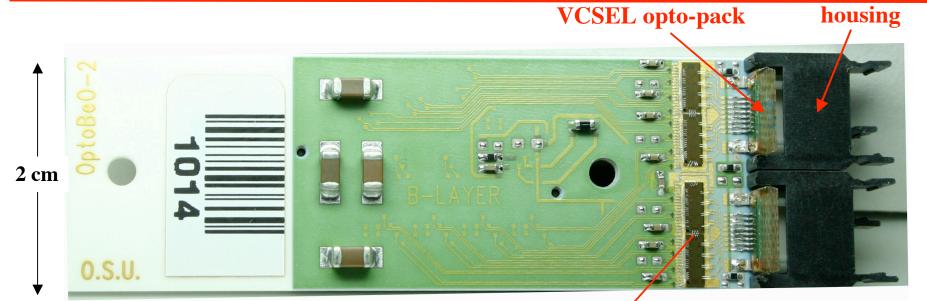


- converts: optical signal ↔ electrical signal
- contains 7 optical links
- use BeO for heat management but prototype initially in FR-4 for fast turnaround and cost saving
- 1st BeO vendor:
 - either under or over filling of vias
 - ⇒ use more experienced/expensive vendor
- 2nd BeO vendor:
 - ◆ 1st prototype: 1-2 SMD detached from few boards
 - remove gold under SMD pads
 - 2nd prototype: SMD pads have much better adhesion
 - remove gold under 80-pin connector pads
 - ⇒ order production opto-boards

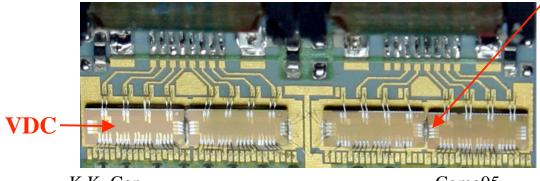


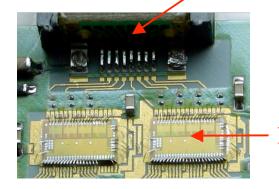
BeO Opto-board





PIN opto-pack



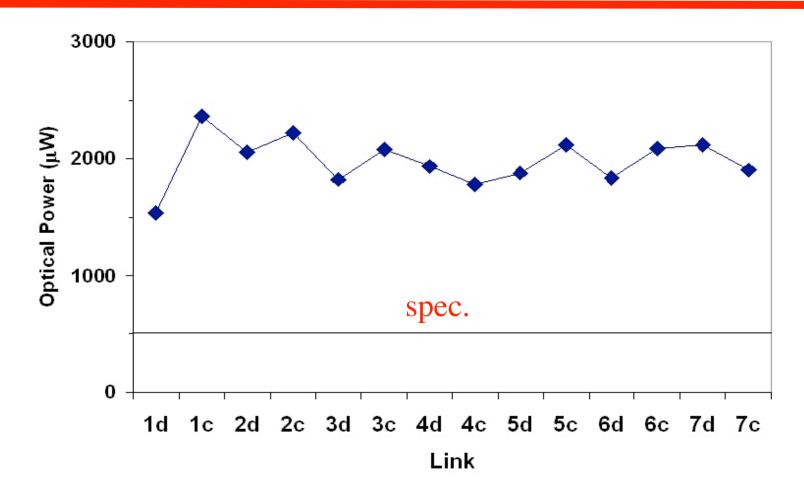


DORIC



Optical Power



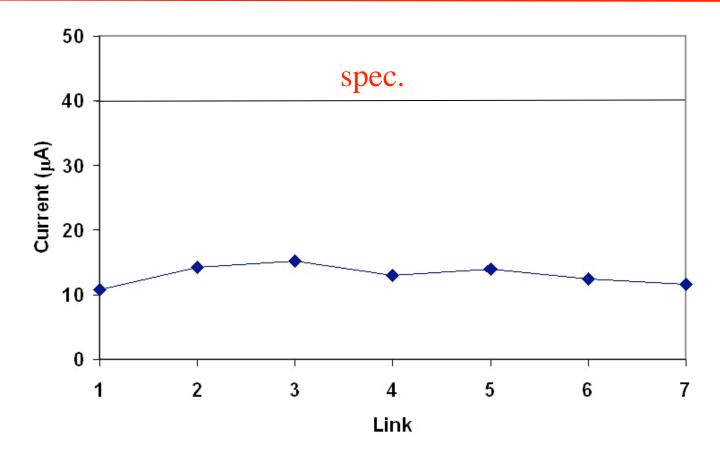


• optical power at 10 mA significantly above spec, 500 μW



Minimum PIN Current for No Bit Errors



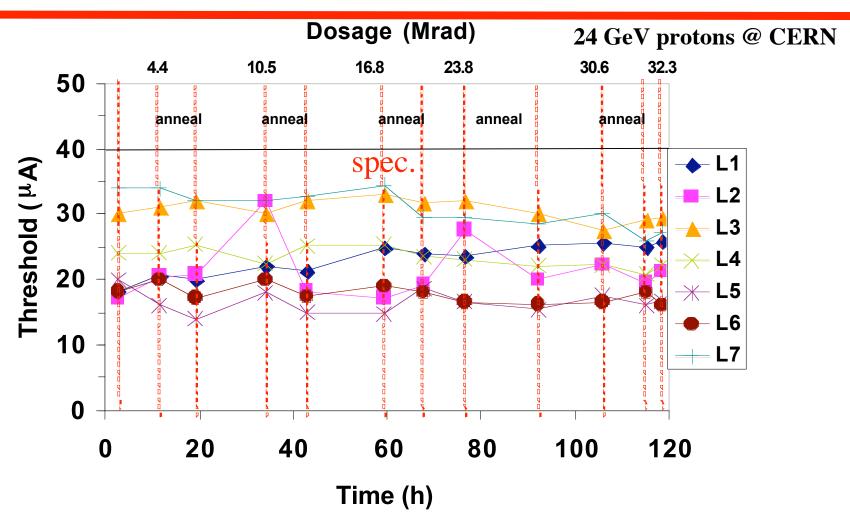


• minimum PIN current for no bit errors with all links active significantly below spec, 40 μA



PIN Current Threshold vs Dosage





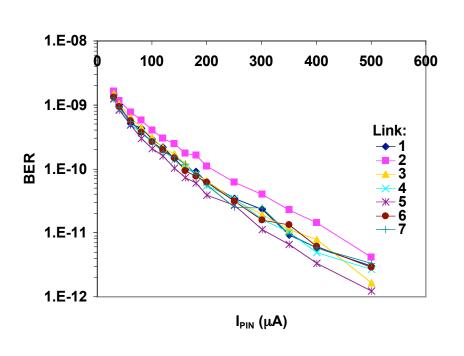
• PIN current thresholds for no bit errors remain constant

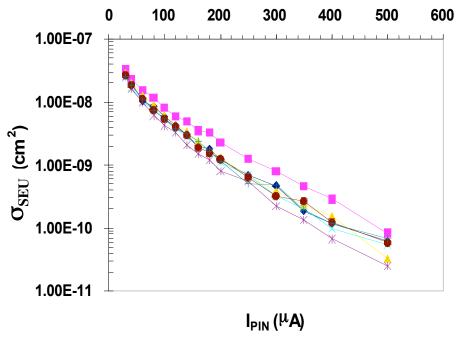


Proton Induced Bit Errors in PIN



• convert observed bit errors into bit error rate at opto-link location:



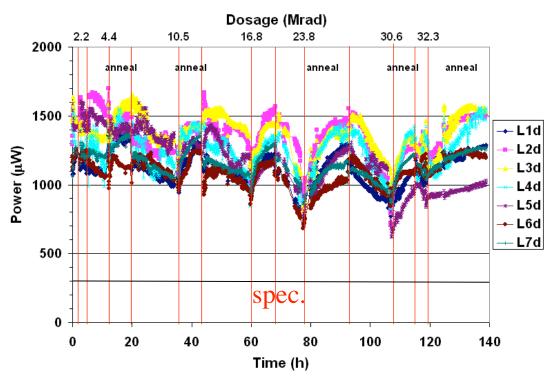


- bit error rate decreases with PIN current as expected
- bit error rate $\sim 3 \times 10^{-10}$ at 100 μ A (1.4 errors/minute)
 - DORIC spec: 10⁻¹¹



Optical Power vs Dosage





- irradiation procedure: ~ 5 Mrad/day (10 hours) with annealing rest of the day
- optical power decreases with dosage as expected
- limited annealing recovers some lost power
- still have good optical power after 30 Mrad K.K. Gan



Opto-Production Challenges



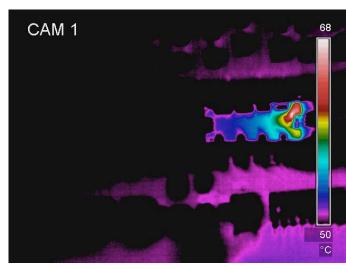
- rigorous QA procedure:
 - ◆ 72 hours of burn-in at 50°C
 - ◆ 18 hours of 10 thermal cycles between -25°C and 50°C
 - 8 hours of optical and electrical measurements
- use 2 ovens and 2 environmental chambers
- implemented an "early shift" to extend the work day
- aggressive goals:
 - producing 10 boards/week
 - ⇒ completed production in early October



Initial Production Problem



- initial plan was not to test chips before mounting on opto-board due to high yield during pre-production
- a bunch of produced boards drawing excessive currents
 - thermal image: power to ground shorts
- ⇒ test chips before mounting







DORIC



Opto-board Rework

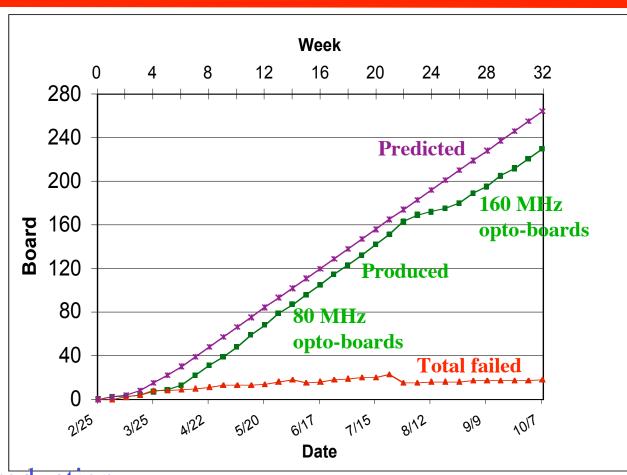


- recover opto-boards by stacking new chips on top of bad chips
- reworked opto-boards must pass same rigorous QA procedure
 - classified as second class for use as spare
- 18 opto-boards have been recovered



Opto-board Production Status





- relatively smooth production
- yield ~ 93%



Summary



- opto-boards of ATLAS pixel detector satisfy design spec. and radiation hardness requirement:
 - ✓ low PIN current thresholds for no bit errors
 - excellent optical power
 - ✓ radiation hard up to ~ 30 Mrad
- simple and modular design allows smooth production
 - production completed in seven months!